

TRADEMARK ASSIGNMENT COVER SHEET

Electronic Version v1.1
Stylesheet Version v1.2

ETAS ID: TM529716

SUBMISSION TYPE:	NEW ASSIGNMENT		
NATURE OF CONVEYANCE:	RELEASE OF SECURITY INTEREST IN INTELLECTUAL PROPERTY		
CONVEYING PARTY DATA			
Name	Formerly	Execution Date	Entity Type
BARCLAYS BANK PLC, AS COLLATERAL AGENT		06/27/2019	Public Limited Company: UNITED KINGDOM
RECEIVING PARTY DATA			
Name:	TERADYNE, INC.		
Street Address:	600 RIVERPARK DRIVE		
City:	NORTH READING		
State/Country:	MASSACHUSETTS		
Postal Code:	01864		
Entity Type:	Corporation: MASSACHUSETTS		
Name:	EAGLE TEST SYSTEMS, INC.		
Street Address:	2200 MILLBROOK DRIVE		
City:	BUFFALO GROVE		
State/Country:	ILLINOIS		
Postal Code:	60089		
Entity Type:	Corporation: DELAWARE		
Name:	LITEPOINT CORPORATION		
Street Address:	965 WEST MAUDE AVENUE		
City:	SUNNYVALE		
State/Country:	CALIFORNIA		
Postal Code:	94085		
Entity Type:	Corporation: DELAWARE		
Name:	NEXTTEST SYSTEMS CORPORATION		
Street Address:	875 EMBEDDED WAY		
City:	SAN JOSE		
State/Country:	CALIFORNIA		
Postal Code:	95138		
Entity Type:	Corporation: DELAWARE		
Name:	GENRAD, LLC		
Street Address:	600 RIVERPARK DRIVE		
City:	NORTH READING		

CH \$665.00 3938268

State/Country:	MASSACHUSETTS
Postal Code:	01864
Entity Type:	Limited Liability Company: MASSACHUSETTS
Name:	ENERGID TECHNOLOGIES CORPORATION
Street Address:	213 BURLINGTON ROAD
City:	BEDFORD
State/Country:	MASSACHUSETTS
Postal Code:	01730
Entity Type:	Corporation: FLORIDA

PROPERTY NUMBERS Total: 26

Property Type	Number	Word Mark
Registration Number:	3938268	BECAUSE TESTING MATTERS
Registration Number:	3772302	NEPTUNE
Registration Number:	3764364	NEPTUNE
Registration Number:	3782019	
Registration Number:	2709152	TERADYNE
Registration Number:	3255049	FLEX
Registration Number:	3250770	ULTRA FLEX
Registration Number:	3542417	ZTEC
Registration Number:	2953600	SIMULYZER
Registration Number:	3678885	IG-XL
Registration Number:	3715674	TERADYNE SELECT PARTNER
Registration Number:	3776297	CLEARVUE
Registration Number:	4536563	IQ
Registration Number:	4527865	LITEPOINT
Registration Number:	4477095	"L" AND "P"
Registration Number:	4036796	IQXSTREAM
Registration Number:	3798163	MULTICOM
Registration Number:	3351465	LITEPOINT
Registration Number:	2911712	IQVIEW
Registration Number:	2881110	EAGLE TEST SYSTEMS
Registration Number:	3525785	CHAMELEON
Registration Number:	3532829	SMARTPIN
Registration Number:	3040252	NEXTEST
Registration Number:	3026946	NEXTEST
Registration Number:	4567185	CYTON
Registration Number:	4825814	ACTIN

CORRESPONDENCE DATA**Fax Number:** 2123108007*Correspondence will be sent to the e-mail address first; if that is unsuccessful, it will be sent using a fax number, if provided; if that is unsuccessful, it will be sent via US Mail.***Phone:** 212.310.8000**Email:** juan.arias@weil.com**Correspondent Name:** Vaishali Mahna**Address Line 1:** Weil, Gotshal & Manges LLP**Address Line 2:** 767 Fifth Avenue**Address Line 4:** NEW YORK, NEW YORK 10153**ATTORNEY DOCKET NUMBER:** V. Mahna-21151.0137**NAME OF SUBMITTER:** Vaishali Mahna**SIGNATURE:** /Vaishali Mahna/**DATE SIGNED:** 06/28/2019**Total Attachments: 32**

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RELEASE OF SECURITY INTEREST IN INTELLECTUAL PROPERTY

This RELEASE OF SECURITY INTEREST IN INTELLECTUAL PROPERTY (the "IP Release"), dated as of June 27, 2019, is made by Barclays Bank PLC ("Barclays"), as collateral agent (the "Collateral Agent") for the Secured Parties (as defined in the Credit Agreement referred to below), in favor of Teradyne, Inc., Eagle Test Systems, Inc., Litepoint Corporation, Nextest Systems Corporation, Genrad, LLC and Energid Technologies Corporation (each, a "Grantor" and collectively, the "Grantors"). Capitalized terms defined in the IP Security Agreements, as applicable, or in the Security Agreement (each as defined below) and not otherwise defined herein are used herein as defined in the IP Security Agreement or in the Security Agreement, as the case may be (and in the event a term is defined differently in the IP Security Agreement and the Security Agreement, the applicable definition shall be the one given to such term in the IP Security Agreement).

WHEREAS, the Collateral Agent and the Grantors, amongst others, are parties to (i) that certain Guarantee and Collateral Agreement, dated as of April 27, 2015 (as amended, restated, amended and restated, supplemented and/or otherwise modified from time to time, the "Security Agreement"), (ii) that certain Trademark Security Agreement, dated as of April 27, 2015, by Teradyne, Inc., Eagle Test Systems, Inc., Litepoint Corporation and Nextest Systems Corporation in favor of Barclays Bank PLC, as collateral agent, (iii) that certain Patent Security Agreement, dated as of April 27, 2015, by Teradyne, Inc. and Litepoint Corporation in favor of Barclays Bank PLC, as collateral agent, (iv) that certain Copyright Security Agreement, dated as of April 27, 2015, by Teradyne, Inc. and Genrad, LLC in favor of Barclays Bank PLC, as collateral agent, (v) that certain Trademark Security Agreement, dated as of May 14, 2018, by Energid Technologies Corporation in favor of Barclays Bank PLC, as collateral agent, (vi) that certain Patent Security Agreement, dated as of May 11, 2018, by Energid Technologies Corporation in favor of Barclays Bank PLC, as collateral agent and (vii) that certain Copyright Security Agreement, dated as of May 14, 2018, by Energid Technologies Corporation in favor of Barclays Bank PLC, as collateral agent. (the agreements specified in clauses (ii) through (vii), collectively, the "IP Security Agreements");

WHEREAS, pursuant to the IP Security Agreements, the Grantors pledged, assigned and granted to the Collateral Agent, on behalf of and for the benefit of the Secured Parties, a security interest in all of such Grantor's right, title and interest in and to the Collateral (as defined below), including the items set forth in Schedule I hereto;

WHEREAS, the Collateral Agent agrees to fully discharge, terminate and release its security interest in all of each Grantor's right, title and interest in and to the Collateral.

NOW, THEREFORE, for good and valuable consideration, the receipt and sufficiency of which are hereby acknowledged, the Collateral Agent hereby agrees as follows:

SECTION 1. Release of Security Interest in Collateral. The Collateral Agent hereby terminates, releases and discharges fully its security interest in all of each Grantor's right, title and interest in and to all Intellectual Property to the extent governed by, arising under, pursuant to, or by virtue of, the laws of the U.S., including the following (the "Collateral");

- (i) any and all Patents;
- (ii) any and all Trademarks;
- (iii) any and all Copyrights;

(iv) any and all registrations and applications for registration for any of the foregoing in the USPTO or the Copyright Office, as applicable, including, without limitation, the registrations and applications for registration of U.S. Patents, Trademarks, and Copyrights set forth in Schedule I, together with all reissues, divisions, continuations, continuations-in-part, extensions, renewals and reexaminations thereof; and

(v) any and all exclusive licenses to one or more Copyrights registered with the Copyright Office.

SECTION 2. Recordation of Release. The Collateral Agent hereby authorizes and requests that the Register of Copyrights, the Commissioner for Patents and the Commissioner for Trademarks and any other applicable government officer record this IP Release. The Collateral Agent further agrees, upon the reasonable request of a Grantor, to execute any other documents and take any further action reasonably necessary in any state, country or jurisdiction that such Grantor may reasonably require to effect the intent and purpose of this IP Release, provided that all such documents are to be prepared by such Grantor, and approved by the Collateral Agent, and the cost and expense of such documents and actions shall be borne solely by such Grantor.

SECTION 3. Delivery. Delivery of an executed signature page to this IP Release by email or other electronic (including in “.pdf” or “.tif” format) means shall be effective as delivery of a manually executed counterpart of this IP Release.

SECTION 4. Governing Law. **THIS IP RELEASE SHALL BE CONSTRUED IN ACCORDANCE WITH AND GOVERNED BY THE LAW OF THE STATE OF NEW YORK.**

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IN WITNESS WHEREOF, the Collateral Agent has caused this IP Release to be duly executed and delivered by its officer thereunto duly authorized as of the date first written above.

BARCLAYS BANK PLC,
as Collateral Agent

By: Robert Walsh

Name:

Title:

Robert Walsh
Assistant Vice President

Signature Page to Teradyne IP Release

TRADEMARK
REEL: 006681 FRAME: 0111

Schedule I

Patents/Pending Patents

Patents

Registered Patents of Teradyne, Inc.:

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	5606262	Manipulator For Automatic Test Equipment Test Head
United States of America	6469493	Low Cost Cmos Tester
United States of America	5795797	Memory Tester Providing Fast Repair Of Memory Chips
United States of America	5736850	Configurable Probe Card For Automatic Test Equipment
United States of America	5773990	Integrated Circuit Test Power Supply
United States of America	6024526	Integrated Prober, Handler and Tester for Semi-Conductor Components
United States of America	5917331	Integrated Circuit Test Method and Structure
United States of America	5604751	Time Linearity Measurement Using A Frequency Locked, Dalsequencer Automatic Test System
United States of America	5606568	Method And Apparatus For Performing Serial And Parallel Scan Testing
United States of America	5657486	Automatic Test Equipment With Pipelined Sequencer
United States of America	5673272	Apparatus And Method For Performing Digital Signal Processing In An Electronic Circuit Tester
United States of America	5689515	High Speed Serial Data Pin For Automatic Test Equipment
United States of America	5737512	Fast Vector Loading For Automatic Test Equipment
United States of America	5754556	Semiconductor Memory Tester With Hardware Accelerators
United States of America	5758776	Integrated Circuit Tray With Flexural Bearings
United States of America	5839769	Expanding Gripper With Elastically Variable Pitch Screw
United States of America	5982182	Interface Apparatus For Automatic Test Equipment With Positioning Modules Incorporating Kinematic Surfaces
United States of America	6360340	Memory Tester With Data Compression
United States of America	6104202	Interface Apparatus For Automatic Test Equipment
United States of America	5929628	Apparatus And Method For Performing Amplitude Calibration In An Electronic Circuit Tester
United States of America	5768155	Fast Undersampling
United States of America	5923675	Semiconductor Tester For Testing Devices With Embedded Memory
United States of America	5921786	Flexible Shielded Laminated Beam For Electrical Contacts And The Like And Method Of Contact Operation
United States of America	5910895	Low Cost, Easy To Use Automatic Test System Software

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	6036023	Heat-Transfer Enhancing Feature for Semiconductor Carriers and Devices
United States of America	6073259	Low Cost Cmos Tester With High Channel Density
United States of America	5854797	Tester with Fast Refire Recovery Time
United States of America	5971156	Semiconductor Chip Tray with Rolling Contact Retention Mechanism
United States of America	5794175	Low Cost Highly Parallel Memory Tester
United States of America	6047293	System For Storing And Searching Named Device For Parameter Data In A Test System For Testing An Integrated Circuit
United States of America	5828674	Production Interface For An Integrated Circuit Test System
United States of America	6049901	Test System For Integrated Circuits Using A Single Memory For Both The Parallel And Scan Modes Of Testing
United States of America	5938780	Method for Capturing Digital Data in an Automatic Test System
United States of America	6097201	System to Simultaneously Test Trays of Integrated Circuit Package
United States of America	5949002	Manipulator For Automatic Test Equipment With Active Compliance
United States of America	5924003	Method of Manufacturing Ball Grid Arrays for Improved Testability
United States of America	5973394	Small Contactor For Test Probes, Chip Packaging and the Like
United States of America	6091062	Method and Apparatus for Temperature Control of a SemiConductor Electrical-Test Contactor Assembly
United States of America	6037787	High Performance Probe Interface for Automatic Test Equipment
United States of America	6133725	A Compensation Technique For Round-Trip Delay
United States of America	6107818	High Speed, Real-Time, State Interconnect for Automatic Test Equipment
United States of America	6286120	Memory Architecture for Automatic Test Equipment Using Vector Module Table
United States of America	6188253	Analog Clock Module
United States of America	5938781	Production Interface For An Integrated Circuit Test System
United States of America	6275962	Remote Test Module for Automatic Test Equipment
United States of America	6215320	High Density Printed Circuit Board
United States of America	6204679	Low Cost Memory Tester With High Throughput
United States of America	6389525	Pattern Generator for a Packet-Based Memory Tester
United States of America	6282682	Automatic Test Equipment Using Sigma-Delta Modulation to Create Reference Levels
United States of America	6374379	Low-Cost Configuration For Monitoring and Controlling Parametric Measurement Units in Automatic Test Equipment
United States of America	6137310	Serial Switch Driver Architecture For Automatic Test Equipment

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	6405333	Fail Array Memory Control Circuit with Selective Input Disable
United States of America	6442724	Failure Capture Apparatus and Method For Automatic Test Equipment
United States of America	6360180	Driver With Transmission Path Loss Compensation
United States of America	6268735	Imbedded Noise Source
United States of America	6397160	Power Sensor Module For Microwave Test System
United States of America	6476628	Semiconductor Parallel Tester
United States of America	6553529	Low Cost Timing System For Highly Accurate Multi-Modal Semiconductor Testing
United States of America	6208510	Integrated Test Cell Cooling System
United States of America	6310486	Integrated Test Cell
United States of America	6550036	Pre-Conditioner For Measuring High Speed Time Intervals Over A Low-Bandwidth Path
United States of America	7004235	Direct Impingement Temperature Control Structure
United States of America	6681351	Easy To Program Automatic Test Equipment
United States of America	6356129	Low Jitter Phase-Locked Loop With Duty-Cycle Control
United States of America	6331783	Circuit And Method For Improved Test and Calibration In Automated Test Equipment
United States of America	6536005	High-Speed Failure Capture Apparatus And Method For Automatic Test Equipment
United States of America	6463395	Shunt Capacitance Compensation Structure And Method For A Signal Channel
United States of America	6292010	Dynamic Pin Driver Combining High Voltage Mode and High Speed Mode
United States of America	6392448	Common-Mode Detection Circuit With Cross-Coupled Compensation
United States of America	6300804	Differential Comparator With Dispersion Reduction Circuitry
United States of America	6281699	Detector With Common Mode Comparator For Automatic Test Equipment
United States of America	6734688	Low Compliance Tester Interface
United States of America	6499118	Redundancy Analysis Method and Apparatus for ATE
United States of America	6486693	Method and Apparatus for Testing Integrated Circuit Chips that Output Clocks for Timing
United States of America	6609077	ATE Timing Measurement Unit and Method
United States of America	6717115	Semiconductor Handler for Rapid Testing
United States of America	6446560	Single Carriage Robotic Monorail Material Transfer System
United States of America	6564350	Testing Frequency Hopping Devices
United States of America	6837125	Automatic Test Head Manipulator With Support Internal To Test Head
United States of America	6291981	Automatic Test Equipment With Narrow Output Pulses
United States of America	6249128	Automated Microwave Test System With Improved Accuracy
United States of America	6694462	Capturing And Evaluating High Speed Data Streams

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	6466007	Method for Manufacturing Smart Card and Identification Devices and The Like
United States of America	6756777	Method for Manufacturing Smart Card and Identification Devices and The Like
United States of America	6396313	Noise-Shaped Digital Frequency Synthesis
United States of America	6642707	High-Speed Peaking Circuit For Characteristic Impedance Control
United States of America	6515499	High Performance Tester Interface Module Div I-Coaxial Cable With Overvoltage Protection for ATE
United States of America	6939175	High Performance Tester Interface Module Div I-Coaxial Cable With Overvoltage Protection for ATE
United States of America	6404369	Digital To Analog Converter Employing Sigma-Delta Loop And Feedback DAC Model
United States of America	6798830	Methods and Apparatus for Generating a Test Signal For XDSL Devices
United States of America	6838868	Test Head Actuation System with Positioning and Compliant Modes
United States of America	6556034	High Speed and High Accuracy DUT Power Supply with Active Boost Circuitry
United States of America	6542385	DUT Power Supply Having Improved Switching DC-DC Converter
United States of America	6675117	Calibrating Single Ended Channels for Differential Performance
United States of America	7337377	Enhanced Loopback Testing of Serial Devices
United States of America	6551122	Low Profile Pneumatically Actuated Docking Module With Power Fault Release
United States of America	6448748	Biasing Circuit For DUT Power Supply
United States of America	6566890	Circuit for Improved Test and Calibration In Automated Test Equipment
United States of America	6452436	Apparatus and Method for Managing Automatic Transitions Between Multiple Feedback Paths
United States of America	6772382	Driver for Integrated Circuit Chip Tester
United States of America	6857089	Differential Receiver Architecture
United States of America	6684169	Facilitating Comparisons Between Simulated and Actual Behavior of Electronic Devices
United States of America	6687630	Low Leakage Technique for Determining Power Spectra of Non-Coherently Sampled Data
United States of America	6784656	Hybrid Conductor-Board for Multi-Conductor Routing
United States of America	6504395	Method and Apparatus for Calibration and Validation of High Performance DUT Power Supplies
United States of America	6617867	Mechanism for Clamping Device Interface Board to Peripheral
United States of America	7146584	Scan Diagnosis System and Method
United States of America	7222041	High-Speed Digital Multiplexer
United States of America	7509227	High-Speed Digital Multiplexer
United States of America	6976183	Clock Architecture For A Frequency-Based Tester
United States of America	6775628	Low Distortion Frequency Tracking Technique
United States of America	6756807	Modular ATE Power Supply Architecture

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	6868047	Compact ATE With Timestamp System
United States of America	6603418	High Precision, High-Speed Signal Source
United States of America	6683550	High Precision, High-Speed Signal Capture
United States of America	6686732	Low-Cost Tester Interface Module
United States of America	6882947	DFT Leakage Removal for Non-Coherently Sampled Signals
United States of America	6697753	Methods and Apparatus for Testing Electronic Devices.
United States of America	6882156	Printed Circuit Board Assembly For Automatic Test Equipment
United States of America	7080304	Technique For Programming Clocks In Automatic Test System
United States of America	7135854	Rear-Mounted Gimbal For Supporting Test Head
United States of America	6686787	High-Speed Fully Balanced Differential Flip-Flop With Reset
United States of America	6885961	Hybrid Tester Architecture
United States of America	6768331	Wafer Level Contactor
United States of America	6759842	Interface Adapter for Automatic Test Systems
United States of America	7017087	Enhanced Loopback Testing of Serial Devices
United States of America	6766411	Circuit For Looping Serial Bit Streams From Parallel Memory
United States of America	7385385	Stackable Semiconductor Test System and Method for Operating Same.
United States of America	6756800	Semiconductor Test System with Easily Changed Interface Unit
United States of America	6717432	Single Axis Manipulator with Controlled Compliance
United States of America	6722215	Manipulator Apparatus With Low-Cost Compliance
United States of America	7222261	Automatic Test Equipment for Test and Analysis of Analog DFT/BIST Circuitry
United States of America	6831473	Ring Calibration Apparatus and Method For Automatic Test Equipment
United States of America	6784819	Measuring Skew Between Digitizer Channels Using Fourier Transform
United States of America	6828774	Rear-Mounted Gimbal For Supporting Test Head
United States of America	6966019	Instrument Initiated Communication For Automatic Test Equipment
United States of America	6771061	High Speed Tester With Narrow Output Pulses
United States of America	6906578	Control Loop Compensation Apparatus and Method
United States of America	6981192	Deskewed Differential Detector Employing Analog-To-Digital Converter
United States of America	6916990	High Power Interface
United States of America	7049577	Semiconductor Handler Interface Auto Alignment
United States of America	6784679	Differential Coaxial Contact Array for High-Density, High-Speed Signals
United States of America	6940298	High Fidelity Electrical Probe
United States of America	6765796	Circuitboard Cover With Exhaust Apertures For Cooling Electronic Components

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	6754868	Semiconductor Test System Having Double Data Rate Pin Scrambling.
United States of America	7143323	High Speed Capture and Averaging of Serial Data by Asynchronous Periodic Sampling
United States of America	6836136	Pin Driver For AC and DC Semiconductor Device Testing
United States of America	7019547	Pin Driver For AC and DC Semiconductor Device Testing
United States of America	7117410	Distributed Failure Analysis Memory For Automatic Test Equipment
United States of America	7003697	Apparatus Having Pattern Scrambler for Testing a Semiconductor Device and Method for Operating Same.
United States of America	6894552	Low-Jitter Delay Cell
United States of America	6864698	Hybrid Cooling System For Automatic Test Equipment
United States of America	6879175	Hybrid AC/DC-Coupled Channel for Automatic Test Equipment
United States of America	7208937	Hybrid AC/DC-Coupled Channel for Automatic Test Equipment
United States of America	7064535	Measurement Circuit With Improved Accuracy
United States of America	7472326	Semiconductor Test System Having Multitasking Algorithmic Pattern Generator.
United States of America	6822498	Clock Distribution System For Automatic Test Equipment
United States of America	7171587	Automatic Test System with Easily Modified Software
United States of America	7636642	Direct Jitter Analysis of Binary Sampled Data
United States of America	6819155	High-Speed Duty-Cycle Control Circuit
United States of America	6990423	Apparatus and Method For Testing Non-Deterministic Device Data
United States of America	7216273	Method For Testing Non-Deterministic Device Data
United States of America	7509226	Apparatus and Method For Testing Non-Deterministic Device Data
United States of America	6919833	Parallel Converter Topology for Reducing Non-Linearity Errors
United States of America	7123075	Current Mirror Compensation Using Channel Length Modulation
United States of America	7061307	Current Mirror Compensation Circuit and Method
United States of America	6958598	Efficient Switching Architecture With Reduced Stub Lengths
United States of America	7863888	Efficient Switching Architecture With Reduced Stub Lengths
United States of America	7064616	Multi-Stage Numeric Counter Oscillator
United States of America	6975130	Techniques For Controlling Movement Of A Circuit Board Module Along A Card Cage Slot
United States of America	7230553	Parallel Source/Capture Architecture
United States of America	6853181	Silicon-On-Insulator Channel Architecture For Automatic Test Equipment

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	7088092	Silicon-On-Insulator Channel Architecture For Automatic Test Equipment
United States of America	6914425	Measurement Circuit With Improved Accuracy
United States of America	7174279	Test System With Differential Signal Measurement
United States of America	7151367	Method Of Measuring Duty Cycle
United States of America	7061276	High Performance Signal Generation
United States of America	7432751	High Performance Signal Generation
United States of America	7161392	Comparator Feedback Peak Detector
United States of America	7535263	Comparator Feedback Peak Detector
United States of America	7061286	Synchronization Between Low Frequency and High Frequency Digital Signals
United States of America	7663389	Automated Test Equipment with DIB Mounted Three Dimensional Tester Electronics Bricks
United States of America	7098650	Apparatus for Planarizing a Probe Card and Method Using Same
United States of America	7085668	Time Measurement Method Using Quadrature Sine Waves
United States of America	7187549	Heat Exchange Apparatus With Parallel Flow
United States of America	7046027	Interface Apparatus For Semiconductor Device Tester
United States of America	7375542	Automated Test Equipment with DIB Mounted Three Dimensional Tester Electronics Bricks
United States of America	7343387	Algorithm For Configuring Clocking System
United States of America	7403030	Using Parametric Measurement Units As A Source Of Power For A Device Under Test
United States of America	7135881	Method And System For Producing Signals To Test Semiconductor Devices
United States of America	7256600	Method And System For Testing Semiconductor Devices
United States of America	7102375	Pin Electronics With High Voltage Functionality
United States of America	7224746	Pre-Compensation for Digital Bit Streams
United States of America	7769559	Instrument with Interface for Synchronization in Automatic Test Equipment
United States of America	7388158	Circuit Board Assembly With Reduced Capacitive Coupling
United States of America	7881397	Wireless Communication System Direct Digital Carrier Modulation Technique
United States of America	7957461	Calibrating Automatic Test Equipment
United States of America	7183953	Calibrating Automatic Test Equipment Containing Interleaved Analog-To-Digital Converters
United States of America	7023366	Using A Parametric Measurement Unit For Converter Testing
United States of America	7253607	Site-Aware Objects
United States of America	7507099	Floating Interface
United States of America	7809999	Ternary search process
United States of America	7312604	Portable Manipulator for Stackable Semiconductor Test System.
United States of America	7254508	Site Loops

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	7856578	Strobe Techniques for Test of Digital Signal Timing
United States of America	7180321	Dual PCB Interface for ATE
United States of America	7389461	Data capture in automatic test equipment
United States of America	7126519	Low-Spur Low-Distortion Digital-To-Analog Converter
United States of America	7541819	Modularized Device Interface With Grounding Insert Between Two Strips
United States of America	7408337	Compensating for Loss in a Transmission Path
United States of America	7323898	Pin Electronics Driver
United States of America	7349818	Jitter Measurement Algorithm For Determining Frequency Components Of Measured Jitter
United States of America	7519490	Jitter Measurement Algorithm For Determining Frequency Components Of Measured Jitter
United States of America	7319936	Instrument with Interface for Synchronization in Automatic Test Equipment
United States of America	7379395	Precise Time Measurement Apparatus And Method
United States of America	7606675	Jitter Measurement Algorithm For Determining Frequency Components Of Measured Jitter
United States of America	7295642	Jitter Compensation And Generation In Testing Communication
United States of America	7352306	Analog-To-Digital Converter With Non-Linearity Compensation
United States of America	7459642	RIM Slot Filler Module and Method of Manufacturing the Same
United States of America	7336748	DDS Circuit With Arbitrary Frequency Control Clock
United States of America	7327816	High Resolution Synthesizer With Improved Signal Purity
United States of America	7221298	Calibration CircuitryDAC Full Rate Sampling Calibration Method
United States of America	7885361	High-Speed Linear Phase DetectorMethod and apparatus for 0/180 degree phase
United States of America	7508228	Method and System for Monitoring Test Signals for Semiconductor Devices
United States of America	7239259	Digitizer With Enhanced Accuracy
United States of America	7598725	Positional Control Manipulator
United States of America	7560947	Pin Electronics Driver
United States of America	7378854	Dual Sine-Wave Time Stamp Method and Apparatus
United States of America	7454681	Automatic Test System With Synchronized Instruments
United States of America	7504822	ATE Instrument Card and Probe Cabling System and Apparatus
United States of America	7492146	Impedance Controlled Via Structure
United States of America	7343558	Configurable automatic-test-equipment system
United States of America	7765080	System for Testing Smart Cards and Methods for same
United States of America	7345549	Phase Locking on Aliased Frequencies
United States of America	7649375	Connector-To-Pad Printed Circuit Board Translator And Method Of Fabrication
United States of America	7480581	Calibrating A Testing Device

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	7946853	Connector-To-Pad Printed Circuit Board Translator And Method Of Fabrication
United States of America	7489146	V/I Source And Test System Incorporating The Same
United States of America	8120375	Probe Card And Method For Using Probe Card, Wafer Prober Utilizing Same
United States of America	7861059	Method For Testing And Programming Memory Devices And Systems For Same.
United States of America	7285851	Liquid Immersion Cooled Multichip Module
United States of America	7890562	Sine Wave Generator With Dual Port Look-Up Table
United States of America	7429939	Signal Analysis Using Dual Converters And Cross Spectrum
United States of America	7523238	Device and method to reduce simultaneous switching noise
United States of America	7519878	Obtaining Test Data For A Device
United States of America	8063727	Conductive Shielding Device
United States of America	7538708	Efficient, Selective Error Reduction For Parallel, Time-Interleaved Analog-To-Digital Converter
United States of America	7590170	Method And Apparatus For Measuring Jitter
United States of America	7487422	Delayed Evaluation For Site-Aware Objects
United States of America	7541958	Error Reduction For Parallel, Time-Interleaved Analog-To-Digital Converter
United States of America	7528623	Distributing Data Among Test Boards To Determine Test Parameters
United States of America	7890822	Tester Input/Output Sharing
United States of America	7643545	Calibrating Automatic Test Equipment To Account For Magnitude And Phase Effects
United States of America	7701232	Rotational Positioner and Methods For Semiconductor Wafer Test Systems
United States of America	7991046	Calibrating Jitter
United States of America	7589548	Design-For-Test Micro Probe
United States of America	7574632	Strobe Technique For Time Stamping A Digital Signal
United States of America	7545224	Cost-Effective, Low-Noise, Single-Loop Synthesizer
United States of America	7523007	Calibration Device
United States of America	7573957	Strobe Technique For Recovering A Clock In A Digital Signal
United States of America	7489125	Calibrating A Tester Using ESD Protection Circuitry Method Of DC Calibration On High Speed Ate Channel Utilizing ESD Diode
United States of America	7554323	Direct Facility Water Test Head Cooling Architecture
United States of America	7668235	Jitter Measurement Algorithm Using Locally In-Order Strobes
United States of America	7593497	Method And Apparatus For Adjustment Of Synchronous Clock Signals
United States of America	7584068	Electrically Stimulated Fingerprint Sensor Test Method
United States of America	7536621	Quantized Data-Dependent Jitter Injection Using Discrete Samples
United States of America	7733081	Automated Test Equipment Interface

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	7561083	Testing of Analog to Digital Converters
United States of America	7888947	Calibrating Automatic Test Equipment
United States of America	7685885	Manipulator Constant Force Spring Counterbalance
United States of America	8046396	Residual Fourier-Padding Interpolation for Instrumentation and Measurement
United States of America	7977583	Shielded Cable Interface Module and Method of Fabrication
United States of America	7595746	Interpolation Digital-to-Analog Converter
United States of America	7816932	Test System With High Frequency Interposer
United States of America	7642802	Method And Apparatus For Cooling Non-Native Instrument In Automatic Test Equipment
United States of America	7847570	Laser Targeting Mechanism
United States of America	7538539	Current Meter With Reduced Range Switching and Load Transients
United States of America	8094766	Tracker Circuit and Method for Automated Test Equipment Systems.
United States of America	8115107	System and Method for Mounting Shielded Cables to Printed Circuit Board Assemblies
United States of America	7719446	Method And Apparatus For Computing Interpolation Factors In Sample Rate Conversion Systems
United States of America	7786718	Time Measurement of Periodic Signals
United States of America	7815466	Coax Cable To Printed Circuit Board Interface Module
United States of America	8521465	General Purpose Protocol Engine
United States of America	8289039	Pin Electronics Liquid Cooled Multi-Module For High Performance, Low Cost Automated Test Equipment
United States of America	8622752	Probe-Card Interposer Constructed Using Hexagonal Modules
United States of America	8692538	Test Equipment Calibration
United States of America	8527231	High Throughput Semiconductor Device Testing
United States of America	7432751	High Performance Signal Generation
United States of America	7673199	A Multiplexed Protocol Allowing Multiple Computers To Talk To Multiple Instruments With High Throughput
United States of America	8400338	Compensating For Harmonic Distortion In An Instrument Channel
United States of America	7933942	Low Cost, High Purity Sign Wave Generator
United States of America	8452560	Identifying Periodic Jitter In A Signal
United States of America	8805636	Protocol Aware Digital Channels Apparatus
United States of America	8725489	A Method for Testing in Reconfigurable Tester
United States of America	7925074	Adaptive Background Propagation Method And Apparatus Therefor
United States of America	8131387	Integrated High Efficiency Microwave Sourcing Control Process Design
United States of America	8461855	A Device Interface Board With Cavity Back For Very High Frequency Applications
United States of America	8471587	Laser Targeting Mechanism
United States of America	7987063	Fast, Low Power Formatter for Automatic Test System

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	8195419	General Purpose Protocol Engine.
United States of America	8128417	Methods and Apparatus for Connecting Printed Circuit Boards Using Zero-Insertion Wiping Force Connections
United States of America	8373432	Automated Test Equipment Employing Test Signal Transmission Channel With Embedded Series Isolation Resistors
United States of America	8269520	Programmable Protocol Generator
United States of America	8805196	Electro-Optical Communications Link
United States of America	8762095	System For Concurrent Test Of Semiconductor Devices
United States of America	8736288	Liquid Cooling During Testing
United States of America	8947537	Rotatable Camera Module Testing System
United States of America	5736862	System For Detecting Faults In Connections Between Integrated Circuits And Circuit-Board Traces
United States of America	5811980	Test System For Determining The Orientation Of Components On A Circuit Board
United States of America	5615219	System And Method Of Programming A Multistation Testing System
United States of America	5861743	Hybrid Scanner For Use In An Improved MDA Tester
United States of America	5727021	Apparatus And Method For Providing A Programmable Delay With Low Fixed Delay
United States of America	5844412	Board Test Apparatus and Method for Fast Capacitance
United States of America	6052809	Method For Generating Test Patterns
United States of America	6128759	Flexible Test Environment For Automatic Test Equipment
United States of America	6449744	Flexible Test Environment For Automatic Test Equipment
United States of America	6194910	Relayless Voltage Measurement In Automatic Test Equipment
United States of America	6363507	Integrated Multi-Channel Analog Test Instrument Architecture
United States of America	6163160	Adjustable Tooling Pin
United States of America	6175230	Circuit-Board Tester With Backdrive-Based Burst Timing
United States of America	6114848	Direct-Measurement Provision Of Safe Backdrive Levels
United States of America	7127506	PC Configuration Fault Analysis
United States of America	6507920	Extending Synchronous Busses by Arbitrary Lengths Using Native Bus Protocol
United States of America	6823479	Network Fault Analysis Tool
United States of America	6622272	Automatic Test Equipment Methods and Apparatus for Interfacing with an External Device
United States of America	7327870	Method For Inspecting A BGA Joint
United States of America	6748046	Off-Center Tomosynthesis
United States of America	6725115	Dynamic Testing Of Electronic Assemblies
United States of America	6618629	Communications Interface for Assembly-Line Monitoring and Control

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	6563352	Driver Circuit Employing High-Speed Tri-State For Automatic Test Equipment
United States of America	6894505	Flexible Interface For Universal Bus Test Instrument
United States of America	7420375	Method for Digital Bus Testing
United States of America	7584029	Telematics-Based Vehicle Data Acquisition Architecture
United States of America	7428218	Flexible Approach for Representing Different Bus Protocols
United States of America	7343279	Universal Approach For Simulating, Emulating, And Testing A Variety Of Serial Bus Types
United States of America	7395479	Over-Voltage Test for Automatic Test Equipment
United States of America	7908531	Networked Test System
United States of America	7819581	Method of and Technique for Calibration of Inspection System Used to Obtain Digital X-ray Images Used in Inspection of Printed Circuit Boards. Formal Title: Method and System for Calibration of X-Ray Systems.
United States of America	7626175	Method of and System of Obtaining Linear Data for Thickness of Object Scanned using Non Collimated, Poly Energetic X-rays.
United States of America	7788564	Adjustable Test Pattern Results Latency.
United States of America	8760183	Fast Open Circuit Detection For Open Power And Ground Pins
United States of America	8618810	Identifying Fuel Cell Defects
United States of America	8031929	X-Ray Inspection of Solder Reflow in High-Density Printed Circuit Board Applications
United States of America	8604820	Test Access Component for Automatic Testing of Circuit Assemblies
United States of America	8760185	Low Capacitance Probe for Testing Circuit Assembly.
United States of America	8310256	Capacitive Opens Testing in Low Signal Environments.
United States of America	7945424	Disk Drive Emulator and Method of Use Thereof
United States of America	8095234	Transferring Disk Drives Within Disk Drive Testing Systems
United States of America	8041449	Bulk Feeding Disk Drives To Disk Drive Testing Systems
United States of America	8102173	Temperature Control Within Disk Drive Testing Systems
United States of America	7848106	Temperature Control Within Disk Drive Testing Systems
United States of America	8117480	Dependent Temperature Control Within Disk Drive Testing Systems
United States of America	7904211	Dependent Temperature Control Within Disk Drive Testing Systems
United States of America	8160739	Transferring Storage Devices Within Storage Device Testing Systems
United States of America	8655482	Enclosed Operating Area for Storage Device Testing Systems
United States of America	8086343	Processing Storage Devices
United States of America	7932734	Conductive Heating

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	8628239	Storage Device Temperature Sensing
United States of America	7778031	Test Slot Cooling System For A System For A Storage Device Testing System
United States of America	8631698	Test Slot Carriers
United States of America	7929303	Storage Device Testing System Cooling
United States of America	8116079	Storage Device Testing System Cooling
United States of America	7908029	Processing Storage Devices
United States of America	8098181	Attenuator Circuit
United States of America	8687349	Bulk Feeding Hard Storage Devices Using Manual Loading
United States of America	8964361	Bulk Feeding Hard Storage Devices Using Manual Loading
United States of America	7996174	Disk Drive Testing
United States of America	8482915	Temperature Control Within Disk Drive Testing Systems
United States of America	8305751	Vibration Isolation Within Disk Drive Testing Systems
United States of America	7911778	Vibration Isolation Within Disk Drive Testing Systems
United States of America	8549912	Disk Drive Transport, Clamping and Testing
United States of America	8467180	Disk Drive Transport, Clamping and Testing
United States of America	8405971	Disk Drive Transport, Clamping and Testing
United States of America	7987018	Transferring Disk Drives Within Disk Drive Testing Systems
United States of America	8712580	Transferring Storage Devices Within Storage Device Testing Systems
United States of America	8140182	Bulk Feeding Disk Drives To Disk Drive Testing Systems
United States of America	8451608	Temperature Control within Storage Device Testing Systems
United States of America	8238099	Enclosed Operating Area For Disk Drive Testing Systems
United States of America	8499611	Disk Drive Emulator and Method of Use Thereof
United States of America	8466699	Conductive Heating
United States of America	8547123	Conductive Heating
United States of America	7995349	Storage Device Temperature Sensing
United States of America	7940529	Storage Device Temperature Sensing
United States of America	7920380	Test Slot Cooling System for a Storage Device Testing System
United States of America	8279603	Test Slot Cooling System for a Storage Device Testing System
United States of America	8687356	Storage Device Testing System Cooling
United States of America	7804349	Timing Signal Generator Providing Synchronized Timing Signals at Non-Integer Clock Multiples Adjustable By More Than One Period
United States of America	8988081	Determining Propagation Delay
United States of America	8310270	Emulating Behavior of a Legacy Test System
United States of America	8745337	Memory Overrun Control
United States of America	8531176	Driving An Electronic Instrument

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	8542005	Connection Digital Storage Oscilloscopes
United States of America	8502522	Multi-Level Triggering Circuit
United States of America	8914566	Managing Interrupts
United States of America	8701130	Implementing Remote Procedure Calls

Registered Patents of LitePoint Corporation:

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	7457995	Method And Apparatus For Generating Reference Transmission Signal For Use In Testing Communications Receivers
United States of America	7363188	Apparatus And Method For Operating Automated Test Equipment (ATE)
United States of America	7167682	Radio Frequency (RF) Transceiver With Substantially Coincident Communication Of RF And Related Control Signals
United States of America	7706250	Apparatus And Method For Simultaneous Testing Of Multiple Orthogonal Frequency Division Multiplexed Transmitters With Single Vector Signal Analyzer
United States of America	7457712	Distributed Test Equipment System For Testing Analog Communications Systems
United States of America	7519383	Method For Efficient Calibration Of EVM Using Compression Characteristics
United States of America	7689213	Method For Testing Embedded Wireless Transceiver With Minimal Interaction Between Wireless Transceiver And Host Processor During Testing
United States of America	7484146	Method For Capturing Multiple Data Packets In A Data Signal For Analysis
United States of America	7564896	Method For Measuring Multiple Parameters Of A Signal Transmitted By A Signal Generator
United States of America	7567521	Apparatus For Capturing Multiple Data Packets In A Data Signal For Analysis
United States of America	7590954	Test Solution Development Method
United States of America	8131223	System For Testing An Embedded Wireless Transceiver
United States of America	7865147	System For Testing An Embedded Wireless Transceiver
United States of America	7822130	Apparatus And Method For Simultaneous Testing Of Multiple Orthogonal Frequency Division Multiplexed Transmitters With Single Vector Signal Analyzer
United States of America	8166340	Apparatus And Method For Testing A Communication Circuit
United States of America	7706250	Apparatus And Method For Simultaneous Testing Of Multiple Orthogonal Frequency Division Multiplexed Transmitters With Single Vector Signal Analyzer

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	7773531	Method For Testing Data Packet Transceiver Using Loop Back Packet Generation
United States of America	7962823	System And Method For Testing Multiple Packet Data Transmitters
United States of America	7772922	Method And System For Testing Data Signal Amplifier Having Output Signal Power Dependent Upon Multiple Power Control Parameters
United States of America	7948254	Digital Communications Test System For Multiple Input, Multiple Output (MIMO) Systems
United States of America	8085685	Method And System For Testing Multiple Data Packet Transceivers Together During A Predetermined Time Interval
United States of America	8036617	Radio Frequency (RF) Signal Generator And Method For Providing Test Signals For Testing Multiple RF Signal Receivers
United States of America	8693351	System And Method For Deterministic Testing Of Packet Error Rate In Electronic Devices
United States of America	8867372	Method For Efficient Parallel Testing Of Time Division Duplex (TDD) Communications Systems
United States of America	8656229	System And Method For Execution Of User-Defined Instrument Command Sequences Using Multiple Hardware And Analysis Modules
United States of America	8189483	Method For Measuring Sensitivity Of Data Packet Signal Receiver
United States of America	8913517	Method For Measuring Sensitivity Of Data Packet Signal Receiver
United States of America	8155175	Method For Measuring Multiple Parameters Of A Signal Transmitted By A Signal Generator
United States of America	8312330	System And Method For Testing Wireless Devices
United States of America	8676188	Apparatus, System And Method For Calibrating And Verifying A Wireless Communication Device
United States of America	8228087	Digital Communications Test System For Multiple Input, Multiple Output (MIMO) Systems
United States of America	8116208	System And Method For Testing Multiple Digital Signal Transceivers In Parallel
United States of America	8170490	Method And Apparatus For Testing Multiple Data Signal Transceivers Substantially Simultaneously With Common Transceiver Tester
United States of America	8509090	Apparatus And Method For Testing A Wireless Transceiver
United States of America	8774024	Achieving Greater Test Efficiencies Using Acknowledgement Signal Suppression
United States of America	8391160	System And Method For Using Multiple Network Addresses To Establish Synchronization Of A Device Under Test And Test Equipment Controlling The Test

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	8402321	System And Method Of Providing Driver Software To Test Controller To Facilitate Testing By Wireless Transceiver Tester Of A Device Under Test
United States of America	8811194	Method For Testing Wireless Devices Using Predefined Test Segments Initiated By Over-The-Air Signal Characteristics
United States of America	8576947	System And Method For Simultaneous MIMO Signal Testing With Single Vector Signal Analyzer
United States of America	8312329	System And Method For Using A Single Vector Signal Generator To Verify Device Under Test
United States of America	8537942	System And Method Of Maintaining Correction Of Dc Offsets In Frequency Down-Converted Data Signals
United States of America	8912804	A Method For Identifying Self-Generated Spurious Signals
United States of America	8693529	Method For Enabling A Device Under Test (DUT) To Retry A Portion Of A Pre-Defined Test Sequence
United States of America	8913504	System And Method For Initiating Testing Of Multiple Communication Devices
United States of America	8774729	System And Method For Synchronized Triggering Of Test Equipment For Testing MIMO Transceivers
United States of America	8839055	System And Method For Execution Of User-Defined Instrument Command Sequences Using Multiple Hardware And Analysis Modules
United States of America	8788892	System And Method For Testing Radio Frequency Devices Under Test Capable Of Communicating Using Multiple Radio Access Technologies
United States of America	8842549	System And Method For Parallel Testing Of Multiple Data Packet Signal Transceivers
United States of America	8842552	Method Of Facilitating Testing Of Multiple Time-Division-Duplex (TDD) Data Packet Signal Transceivers
United States of America	8934849	System And Method For Confirming Radio Frequency (RF) Signal Connectivity With Device Under Test
United States of America	8811461	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
United States of America	8917761	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
United States of America	8780966	System And Method For Testing A Data Packet Signal Transceiver
United States of America	8885483	System And Method For Testing A Data Packet Signal Transceiver
United States of America	8879659	System And Method For Testing Multiple Data Packet Signal Transceivers

Registered Patents of Energid Technologies Corporation:

<u>Jurisdiction</u>	<u>Patent No.</u>	<u>Title</u>
United States of America	6,757,587	Method and Apparatus for Dynamiccaly Reprogramming Autonomous Agents
United States of America	7,680,300	Visual Object Recognition and Tracking
United States of America	8,301,421	Automatic Control System Generation for Robot Design Validation
United States of America	8,408,918	Method and Apparatus for Haptic Simulation
United States of America	8,428,781	Systems and Methods for Coordination Control for Robot Manipulation
United States of America	9,357,708	Flexible Robotic Manipulation Mechanism

Pending Patent Applications of Teradyne, Inc.:

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
United States of America	US-2014-0184257-A1	Interface For A Test System
United States of America	14084414	Interconnect For Transmitting Signals Between A Device And A Tester
United States of America	14073739	Automated Test System With Event Detection Capability
United States of America	14083985	Automated Test System With Edge Steering
United States of America	14536928	Assembling Devices For Probe Card Testing
United States of America	14316164	Structure For Transmitting Signals In An Application Space Between A Device Under Test And Test Electronics
United States of America	14322375	Edge Generator-Based Phase Locke3d Loop Reference Clock Generator For Automated Test System
United States of America	14225951	Current Regulation For Accurate And Low-Cost Voltage Measurements At The Wafer Level
United States of America	14225918	Equi-Resistant Probe Distribution For High-Accuracy Voltage Measurements At The Wafer Level
United States of America	14254363	Circuitry To Protect A Test Instrument
United States of America	14332757	3D coaxial structure
United States of America	14470574	One-Shot Circuit
United States of America	14471726	Multi-Stage Equalization

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
United States of America	14626252	An All-Electronic Virtual Distance Test Technique For Automotive Radar Applications
United States of America	14614326	High Speed Data Transfer Using Calibrated, Single-Clock Source Synchronous Serializer-Deserializer Protocol
United States of America	14520571	Thermal Control
United States of America	14582648	Braking System
United States of America	62056092	Gripper For Automation
United States of America	14577687	Controlling A Per-Pin Measurement Unit
United States of America	US-2013-0018613-A1	ATE To Detect Signal Characteristics Of A DUT
United States of America	US-2013-0102091-A1	Test System Supporting Simplified Configuration For Controlling Test Block Concurrency
United States of America	US-2013-0260485-A1	Edge Triggered Calibration
United States of America	US-2013-0229068-A1	High Reliability, High Voltage Switch
United States of America	US-2014-0143600-A1	Debugging In A Semiconductor Device Test Environment
United States of America	US-2014-0182813-A1	Test System Having Liquid Containment Chambers Over Connectors
United States of America	US-2014-0207402-A1	Embedded Tester
United States of America	US-2014-0281776-A1	Method And Apparatus For Device Testing Using Multiple Processing Paths
United States of America	US-2014-0240519-A1	Matrix Testing Targets
United States of America	US-2014-0266270-A1	Smooth Vi Mode Crossover Method At Compliance Limit Threshold
United States of America	US-2014-0278177-A1	Method And Apparatus For Low Latency Communication In An Automatic Testing System
United States of America	US-2014-0361798-A1	Calibration Device
United States of America	US-2015-0067382-A1	Synchronizing Data From Different Clock Domains
United States of America	14329617	Controlling Signal Path Inductance In Automatic Test Equipment
United States of America	14468094	Capacitive Opens Testing of Low Profile Components
United States of America	US-2011-0204910-A1	Method And Apparatus For Testing Electrical Connections On A Printed Circuit Board
United States of America	US-2014-0306728-A1	Electronic Assembly Test System

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
United States of America	US-2012-0050903-A1	Engaging Test Slots
United States of America	US-2013-0108253-A1	Controlling The Temperature Of An Object
United States of America	13053651	Bulk Transfer Of Storage Devices Using Manual Loading
United States of America	14464852	Probe Alignment
United States of America	US-2011-0305132 A1	Management Of Air-Borne Vibration
United States of America	US-2011-0310724-A1	Damping Vibrations Within Storage Device Testing Systems
United States of America	US-2013-0071224-A1	Storage Device Testing Systems
United States of America	US-2013-0256967-A1	Managing Energy Transmission
United States of America	US-2014-0271064-A1	Parallel Operation Of Systems Components
United States of America	US-2014-0262149-A1	Air Circulation In A System
United States of America	US-2013-0124134-A1	Fast Signal-Ended To Differential Converter
United States of America	US-2013-0111505-A1	Programmable Test Instrument
United States of America	US-2013-0110446-A1	Test Instrument Having A Configurable Interface
United States of America	US-2013-0110445-A1	Programmable Test Instrument
United States of America	US-2015-0074653-A1	Executing Code On A Test Instrument In Response To An Event
Patent Cooperation Treaty	2014/130295	Matrix Testing Targets
Patent Cooperation Treaty	2014/130307	Rotatable Camera Module Testing System
Patent Cooperation Treaty	WO 2014/105242 A1	Test System Having Liquid Containment Chambers Over Connectors
Patent Cooperation Treaty	WO 2014/143386	Method And Apparatus For Device Testing Using Multiple Processing Paths
Patent Cooperation Treaty	WO 2014/197208	Calibration Device
Patent Cooperation Treaty	WO2014/078196	Debugging In A Semiconductor Device Test Environment
Patent Cooperation Treaty	WO2014/105243	Interface For A Test System
Patent Cooperation Treaty	WO2014/149975	Method And Apparatus For Low Latency Communication In An Automatic Testing System
Patent Cooperation	WO2014159090A1	Smooth Vi Mode Crossover Method At Compliance

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
Treaty		Limit Threshold
Patent Cooperation Treaty	PCTUS2014010418	Embedded Tester
Patent Cooperation Treaty	PCTUS2014061933	Automated Test System With Event Detection Capability
Patent Cooperation Treaty	PCTUS2014066295	Automated Test System With Edge Steering
Patent Cooperation Treaty	PCTUS2014063646	Interconnect For Transmitting Signals Between A Device And A Tester
Patent Cooperation Treaty	PCTUS2015021203	Current Regulation For Accurate And Low-Cost Voltage Measurements At The Wafer Level
Patent Cooperation Treaty	PCTUS2015021206	Equi-Resistant Probe Distribution For High-Accuracy Voltage Measurements At The Wafer Level
Patent Cooperation Treaty	WO2014168694	Electronic Assembly Test System
Patent Cooperation Treaty	WO2014/149605	Air Circulation In A System
Patent Cooperation Treaty	WO2014/149606	Parallel Operation Of Systems Components
Patent Cooperation Treaty	WO2013/062691	Programmable Test Instrument
Patent Cooperation Treaty	WO2013/062692	Test Instrument Having A Configurable Interface
Patent Cooperation Treaty	PCTUS2012056250	Programmable Test Instrument
Patent Cooperation Treaty	PCTUS2012056228	Determining Propagation Delay

Pending Patent Applications of LitePoint Corporation:

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
United States of America	US-2013-0301694-A1	System And Method For Testing A Radio Frequency (RF) Multiple-Input-Multiple-Output (MIMO) Device Under Test (DUT)
United States of America	US-2015-0058691-A1	Method For Testing Data Packet Signal Transceiver Using Coordinated Transmitted Data Packet Signal Power
United States of America	US-2015-0067417-A1	Method For Testing Data Packet Signal Transceivers With Multiple Radio Access Technologies Using Interleaved Device Setup And Testing
United States of America	11931566	Apparatus And Method For Operating Automated Test Equipment (ATE)

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
United States of America	14082378	System And Method For Data Packet Transceiver Testing After Signal Calibration And Power Settling To Minimize Test Time
United States of America	14146257	System And Method For Concurrently Testing Multiple Packet Data Signal Transceivers Capable Of Communicating Via Multiple Radio Access Technologies
United States of America	14609821	System And Method For Testing A Radio Frequency (RF) Multiple-Input-Multiple-Output (MIMO) Device Under Test (DUT)
United States of America	14565634	System And Method For Confirming Radio Frequency (RF) Signal Connection Integrity With Multiple Devices Under Test (DUTS) To Be Tested Concurrently
United States of America	US-2015-0078196-A1	System And Method For Testing Wide Band Data Packet Signal Transceivers Using Narrow Band Testers
United States of America	14147159	System And Method For Testing Data Packet Transceivers Having Varied Performance Characteristics And Requirements Using Standard Test Equipment
United States of America	14084762	System And Method For Enabling Testing A Data Link Of A Data Packet Signal Transceiver
United States of America	14087584	System And Method For Dynamic Signal Interference Detection During Testing Of A Data Packet Signal Transceiver
United States of America	14243166	Radio Frequency Signal Path With Substantially Constant Phase Shift Over Wide Frequency Band
United States of America	14202104	System And Method For Testing A Radio Frequency Transceiver By Controlling Test Flow Via An Induced Interrupt
United States of America	14187926	Method For Testing Multiple Wireless Data Packet Signal Transceivers Using Shared Testing Resources
United States of America	US-2014-0327429-A1	Vector Network Power Meter
United States of America	14256095	Method For Testing Multiple Data Packet Transceivers With A Shared Tester To Maximize Tester Use And Minimize Test Time
United States of America	14476855	System And Method For Capturing And Enabling Analysis Of Test Data Packets From A Radio Frequency Data Packet Signal Transceiver
United States of America	14300358	Method And System For Testing A Radio Frequency Data Packet Signal Transceiver At A Low Network Media Layer
United States of America	14450071	Isolation, Extraction and Evaluation of Transient Distortions from a Composite Signal

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
United States of America	14461573	Method For Testing Implicit Beamforming Performance Of A Multiple-Input Multiple-Output Radio Frequency Data Packet Signal Transceiver
United States of America	US-2014-0024315-A1	System And Method For Facilitating Comparison Of Radio Frequency (RF) Data Signals Transmitted By A Device Under Test (DUT) And Received By A Test System
United States of America	US-2014-0181601-A1	Method Of Testing Multiple Data Packet Signal Transceivers Concurrently
United States of America	US-2012-0121000-A1	Digital Communications Test System For Multiple Input, Multiple Output (MIMO) Systems
United States of America	US-2012-0121001-A1	Digital Communications Test System For Multiple Input, Multiple Output (MIMO) Systems
United States of America	US-2013-0326274-A1	Method For Transferring To A Device By A Tester, Within A Pre-Defined Test Sequence, One Or More Identity And Operational Values
United States of America	US-2014-0233405-A1	System And Method For Testing Multiple Data Packet Signal Transceivers Concurrently
United States of America	US-2014-0256268-A1	System And Method For Confirming Radio Frequency (RF) Signal Connection Integrity With Multiple Devices Under Test (DUTS) To Be Tested Concurrently
United States of America	US-2014-0266929-A1	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
United States of America	US-2014-0273873-A1	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
United States of America	US-2014-0266930-A1	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
United States of America	US-2014-0269870-A1	System And Method For Testing A Radio Frequency Multiple-Input Multiple-Output Data Packet Transceiver While Forcing Fewer Data Streams
United States of America	US-2015-0036729-A1	Method For Testing Sensitivity Of A Data Packet Signal Transceiver
United States of America	US-2015-0063133-A1	Method For Testing Data Packet Signal Transceivers Using Interleaved Device Setup And Testing
United States of America	US-2014-0233405-A1	System And Method For Enabling Automated Testing Of Wireless Data Packet Signal Transceivers
United States of America	US-2014-0327429-A1	Vector Network Power Meter
Patent Cooperation Treaty	WO 2012/030491 A2	Method For Testing Wireless Devices Using Predefined Test Segments Initiated By Over-The-Air Signal Characteristics
Patent Cooperation Treaty	WO 2014/035511	System And Method For Testing Radio Frequency Devices Under Test Capable Of Communicating Using

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
		Multiple Radio Access Technologies
Patent Cooperation Treaty	WO 2014/130114	System And Method For Testing Multiple Data Packet Signal Transceivers Concurrently
Patent Cooperation Treaty	WO 2014/144410	System And Method For Testing A Radio Frequency Multiple-Input Multiple-Output Data Packet Transceiver While Forcing Fewer Data Streams
Patent Cooperation Treaty	WO 2014/197185	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
Patent Cooperation Treaty	WO 2014/197186	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
Patent Cooperation Treaty	WO 2014/197187	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
Patent Cooperation Treaty	WO 2014-137460	System And Method For Confirming Radio Frequency (RF) Signal Connectivity With Device Under Test
Patent Cooperation Treaty	WO 2015/020761	Method For Testing Sensitivity Of A Data Packet Signal Transceiver
Patent Cooperation Treaty	WO 2015/041767	System And Method For Testing Wide Band Data Packet Signal Transceivers Using Narrow Band Testers
Patent Cooperation Treaty	WO2013/112220	System And Method Of Maintaining Correction Of DC Offsets In Frequency Down-Converted Data Signals
Patent Cooperation Treaty	WO2013/158229	Method For Measuring Sensitivity Of Data Packet Signal Receiver
Patent Cooperation Treaty	WO2013/165772	Method For Efficient Parallel Testing Of Time Division Duplex (TDD) Communications Systems
Patent Cooperation Treaty	WO2014/099099	Method Of Testing Multiple Data Packet Signal Transceivers Concurrently
Patent Cooperation Treaty	WO2014/137459	System And Method For Confirming Radio Frequency (RF) Signal Connection Integrity With Multiple Devices Under Test (DUTS) To Be Tested Concurrently
Patent Cooperation Treaty	WO2014/149422	System And Method For Testing A Data Packet Signal Transceiver
Patent Cooperation Treaty	WO2014/149610	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
Patent Cooperation Treaty	WO2014/149622	System And Method For Testing Radio Frequency Wireless Signal Transceivers Using Wireless Test Signals
Patent Cooperation Treaty	WO2014182669	Vector Network Power Meter
Patent Cooperation Treaty	WO2015/026453	Method For Testing Data Packet Signal Transceiver Using Coordinated Transmitted Data Packet Signal

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
		Power
Patent Cooperation Treaty	WO2015/034620	System And Method For Testing Multiple Data Packet Signal Transceivers
Patent Cooperation Treaty	WO2015/034624	Method For Testing Data Packet Signal Transceivers Using Interleaved Device Setup And Testing
Patent Cooperation Treaty	WO2015/034625	Method For Testing Data Packet Signal Transceivers With Multiple Radio Access Technologies Using Interleaved Device Setup And Testing
Patent Cooperation Treaty	PCTUS2013069212	System And Method For Parallel Testing Of Multiple Data Packet Signal Transceivers
Patent Cooperation Treaty	PCTUS2013069432	Method Of Facilitating Testing Of Multiple Time-Division-Duplex (TDD) Data Packet Signal Transceivers
Patent Cooperation Treaty	PCTUS2014018326	System And Method For Testing A Data Packet Signal Transceiver
Patent Cooperation Treaty	PCTUS2014070480	System And Method For Testing Data Packet Transceivers Having Varied Performance Characteristics And Requirements Using Standard Test Equipment
Patent Cooperation Treaty	PCTUS2014064938	System And Method For Data Packet Transceiver Testing After Signal Calibration And Power Settling To Minimize Test Time
Patent Cooperation Treaty	PCTUS2014064984	System And Method For Enabling Testing A Data Link Of A Data Packet Signal Transceiver
Patent Cooperation Treaty	PCTUS2014064995	System And Method For Dynamic Signal Interference Detection During Testing Of A Data Packet Signal Transceiver
Patent Cooperation Treaty	PCTUS2015014620	System And Method For Enabling Automated Testing Of Wireless Data Packet Signal Transceivers
Patent Cooperation Treaty	PCTUS2015019103	Radio Frequency Signal Path With Substantially Constant Phase Shift Over Wide Frequency Band
Patent Cooperation Treaty	PCTUS2014070490	System And Method For Concurrently Testing Multiple Packet Data Signal Transceivers Capable Of Communicating Via Multiple Radio Access Technologies
Patent Cooperation Treaty	PCTUS2015014632	System And Method For Testing A Radio Frequency Transceiver By Controlling Test Flow Via An Induced Interrupt
Patent Cooperation Treaty	PCTUS2015012264	Method For Testing Multiple Wireless Data Packet Signal Transceivers Using Shared Testing Resources
Patent Cooperation Treaty	PCTUS2015019111	Method For Testing Multiple Data Packet Transceivers With A Shared Tester To Maximize Tester Use And Minimize Test Time

Pending Patent Applications of Energid Technologies Corporation:

<u>Jurisdiction</u>	<u>Publication No. / Serial No.</u>	<u>Title</u>
United States of America	14/154,873	Digital Proxy Simulation of Robotic Hardware
United States of America	15/142,157	System and Method for Evaluation of Object Autonomy
United States of America	15/254,383	System and Method for Game Theory-Based Design of Robotic Systems

Trademarks

Registered Trademarks of Teradyne, Inc.:

<u>Jurisdiction</u>	<u>Mark Title</u>	<u>Registration No.</u>	<u>Registration Date</u>	<u>Class</u>	<u>WGS File Ref.</u>
United States of America	Because Testing Matters (Block)	3938268	29-Mar-11	09 Int., 42 Int.	T0529.20007us00
United States of America	Neptune (Block)	3772302	6-Apr-10	09 Int.	T0529.20028us00
United States of America	Neptune (Design Plus Character(S))	3764364	23-Mar-10	09 Int.	T0529.20029us00
United States of America	Design (Miscellaneous Design)	3782019	27-Apr-10	09 Int.	T0529.20030us00
United States of America	Teradyne (Block)	2709152	22-Apr-03	09 Int.	T0529.20032us00
United States of America	Flex (Stylized) (Word Mark (Stylized))	3255049	26-Jun-07	09 Int.	T0529.20047us00
United States of America	Ultra Flex (Block)	3250770	12-Jun-07	09 Int.	T0529.20048us00
United States of America	Ztec (Block)	3542417	9-Dec-08	09 Int.	T0529.20054us00
United States of America	Simulyzer (Block)	2953600	17-May-05	09 Int.	T0529.20058us00
United States of America	IG-XL	3678885	8-Sep-09	09 Int.	T0529.20049US00
United States of America	TERADYNE select partner	3715674	24-Nov-09	09 Int.	T0529.20027US00
United States of America	CLEARVUE	3776297	13-Apr-10	09 Int.	T0529.20005US00

Registered Trademarks of LitePoint Corporation:

<u>Jurisdiction</u>	<u>Mark Title</u>	<u>Registration No.</u>	<u>Registration Date</u>	<u>Class</u>	<u>Vender Price Ref.</u>
United States of America	IQ	4536563	26-Aug-13	09 Int.	11602.00.0110
United States of America	LITEPOINT	4527865	13-May-14	09 Int.	11602.00.0085
United States of America	Design	4477095	4-Feb-14	09 Int.	11602.00.0084
United States of America	IQXSTREAM	4036796	11-Oct-2011	09 Int.	11602.00.0043

<u>Jurisdiction</u>	<u>Mark Title</u>	<u>Registration No.</u>	<u>Registration Date</u>	<u>Class</u>	<u>Vender Price Ref.</u>
United States of America	MULTICOM	3798163	8-Jun-2010	042 Int.	11602.00.0036
United States of America	LITEPOINT	3351465	11-Dec-07	09 Int.	11602.00.0028
United States of America	IQ VIEW	2911712	4-Dec-04	09 Int.	11602.00.0011

Registered Trademarks of Eagle Test Systems, Inc.:

<u>Jurisdiction</u>	<u>Mark Title</u>	<u>Registration No.</u>	<u>Registration Date</u>	<u>Class</u>	<u>WGS File Ref.</u>
United States of America	Eagle Test Systems (Block)	2881110	29-Aug-03	09 Int.	
United States of America	CHAMELEON	3525785	28-Oct-08 Renewal due by 4/28/2015	09 Int.	T0529.20025US00
United States of America	SMARTPIN	3532829	11-Nov-08 Renewal due by 5/11/2015	09 Int.	T0529.20026US00

Registered Trademarks of Nextest Systems Corporation:

<u>Jurisdiction</u>	<u>Mark Title</u>	<u>Registration No.</u>	<u>Registration Date</u>	<u>Class</u>	<u>WGS File Ref.</u>
United States of America	Nextest (Block)	3040252	14-Apr-04	41 Int., 42 Int.	T0529.20036US01
United States of America	Nextest (Block)	3026946	14-Apr-04	09 Int.	T0529.20036US00

Registered Trademarks of Energid Technologies Corporation:

<u>Jurisdiction</u>	<u>Mark Title</u>	<u>Registration No.</u>	<u>Registration Date</u>
United States of America	Cyton	4567185	07/15/2014
United States of	Actin	4825814	10/06/2015

<u>Jurisdiction</u>	<u>Mark Title</u>	<u>Registration No.</u>	<u>Registration Date</u>
America			

Copyrights

Registered Copyrights of Teradyne, Inc.:

<u>Title</u>	<u>Type of Work</u>	<u>Registration Number</u>	<u>Registration Date</u>	<u>Security Interest</u>
Application guide, series II, NT-519.	Text	TX0001248532	12/21/1983	None outstanding
Scot installation guide: series 2.	Text	TX0001311285	3/26/1984	None outstanding
Scot product policy guide: NT-523-00, issue 3.	Text	TX0001391986	7/19/1984	None outstanding
Scot technical manual: series 2.	Text	TX0001311274	3/23/1984	None outstanding
Scot technical manual: series II, NT-513.	Text	TX0001268394	12/27/1983	None outstanding
Supervisor resource manual : 4T-112-00 : issue 1	Text	TX0001285715	2/10/1984	None outstanding
Teradyne Central instructor's guide for Scot operator's training using self-paced instruction.	Text	TX0001347834	5/22/1984	None outstanding

Registered Copyrights of Genrad, LLC:

<u>Title</u>	<u>Type of Work</u>	<u>Registration Number</u>	<u>Registration Date</u>	<u>Security Interest</u>
Genrad catalog...	Serial	TX0000121394	10/16/1978	None outstanding
Introduction to in-circuit testing.	Text	TX0001578800	3/04/1985	Assignment of copyright registrations and copyrights from Genrad, Inc., to Bank of New England (V2198P213)

<u>Title</u>	<u>Type of Work</u>	<u>Registration Number</u>	<u>Registration Date</u>	<u>Security Interest</u>
Digital test library version 2.1.0.	Computer File	TX0005757336	7/31/2003	None outstanding
Digital test library : v 3.2.0	Computer File	TX0005810079	7/31/2003	None outstanding
Digital test generator version 3.2.0.	Computer File	TX0005793183	7/30/2003	None outstanding
Digital test library version 4.0.	Computer File	TX0005793182	7/30/2003	None outstanding
Release 4.4.1 228x software	Computer File	TX0005309036	11/14/2000	None outstanding

Registered Copyrights of Energid Technologies Corporation:

<u>Title</u>	<u>Registration Number</u>	<u>Registration Date</u>
Control Expression Core	TXu001371991	August 20, 2007
Control Expression AB Core	TXu001371990	August 20, 2007
Position Control System	TXu001370975	August 20, 2007